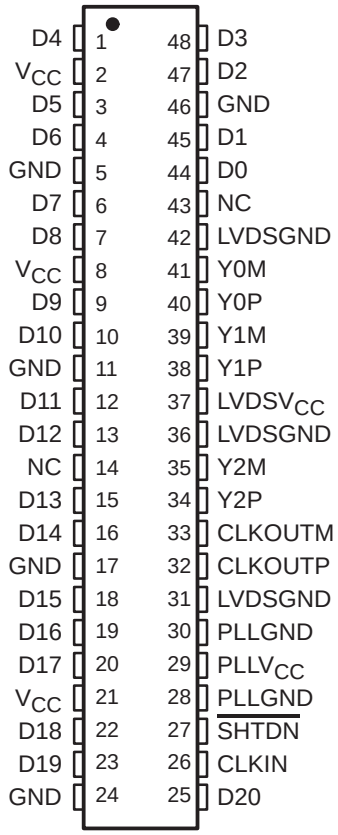
- **21:3 Data Channel Compression at up to 196 Million Bytes per Second Throughput**
- **Suited for SVGA, XGA, or SXGA Data Transmission From Controller to Display With Very Low EMI**
- **21 Data Channels Plus Clock In Low-Voltage TTL Inputs and 3 Data Channels Plus Clock Out Low-Voltage Differential Signaling (LVDS) Outputs**
- **Operates From a Single 3.3-V Supply and 89 mW (Typ)**
- **Ultralow-Power 3.3-V CMOS Version of the SN75LVDS84. Power Consumption About One Third of the ’LVDS84**
- **Packaged in Thin Shrink Small-Outline Package (TSSOP) With 20 Mil Terminal Pitch**
- **Consumes Less Than 0.54 mW When Disabled**
- **Wide Phase-Lock Input Frequency Range: 31 MHz to 75 MHz**
- **No External Components Required for PLL**
- **Outputs Meet or Exceed the Requirements of ANSI EIA/TIA-644 Standard**
- **SSC Tracking Capability of 3% Center Spread at 50-kHz Modulation Frequency**
- **Improved Replacement for SN75LVDS84 and NSC’s DS90CF363A 3-V Device**

DGG PACKAGE
(TOP VIEW)



NC – Not Connected

description

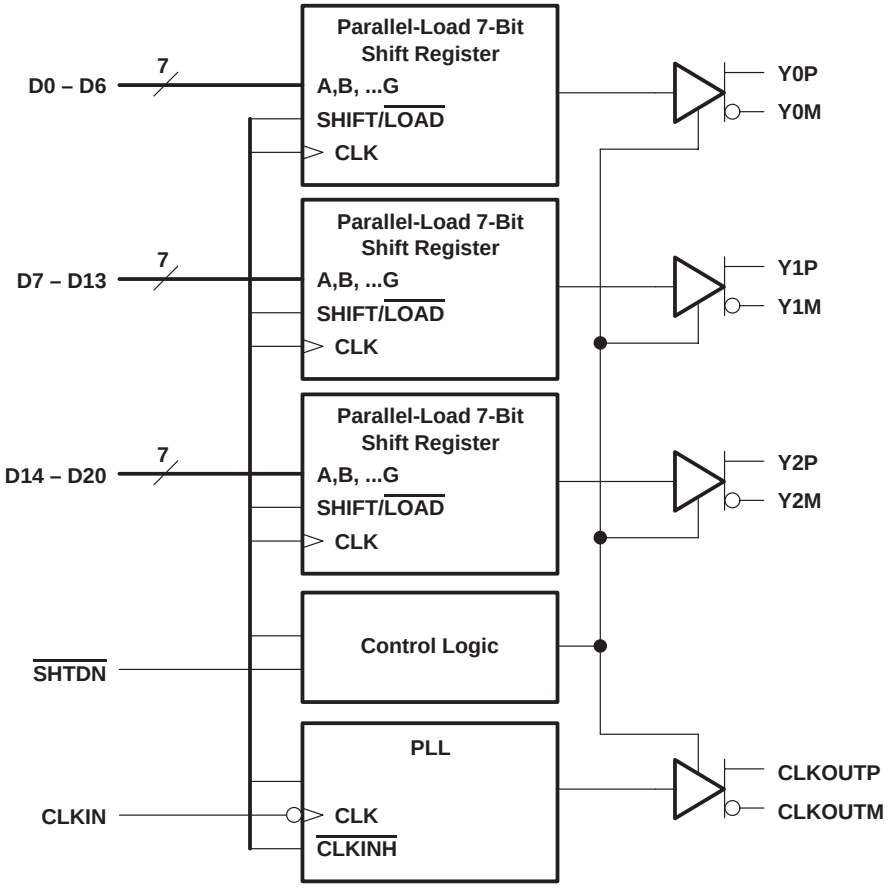
The SN75LVDS84A FlatLink transmitter contains three 7-bit parallel-load serial-out shift registers, and four low-voltage differential signaling (LVDS) line drivers in a single integrated circuit. These functions allow 21 bits of single-ended LVTTL data to be synchronously transmitted over 3 balanced-pair conductors for receipt by a compatible receiver, such as the SN75LVDS82 or SN75LVDS86/86A.

When transmitting, data bits D0 – D20 are each loaded into registers of the ’LVDS84A upon the falling edge. The internal PLL is frequency-locked to CLKIN and then used to unload the data registers in 7-bit slices. The three serial streams and a phase-locked clock (CLKOUT) are then output to LVDS output drivers. The frequency of CLKOUT is the same as the input clock, CLKIN.

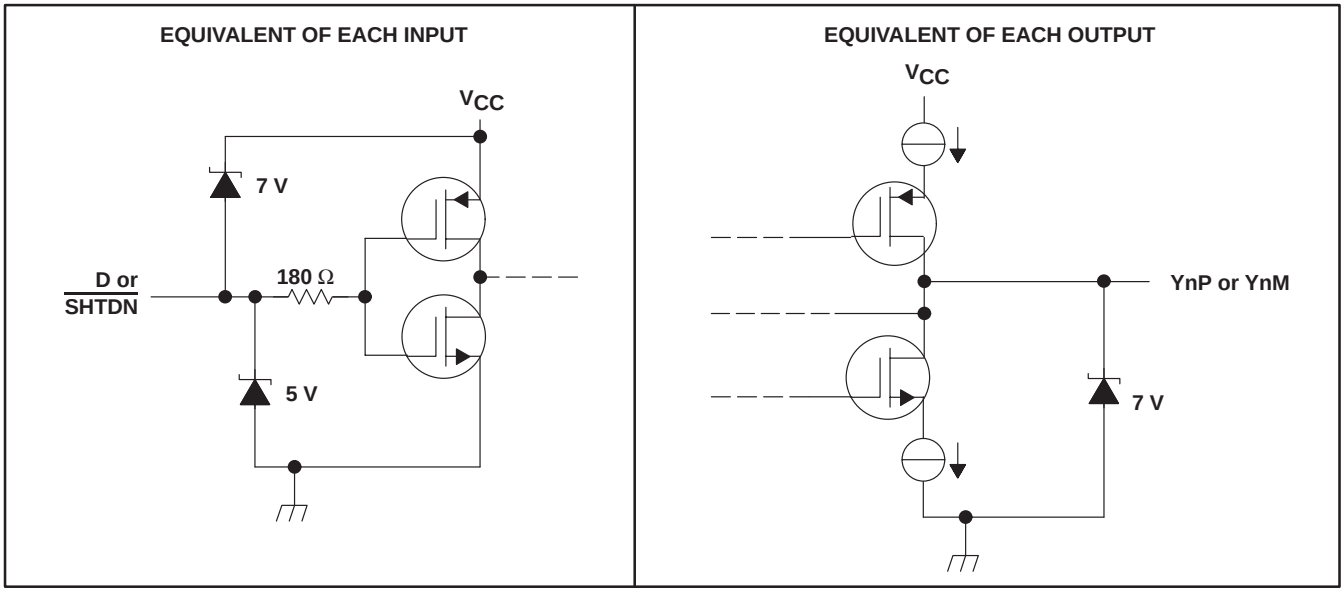
The ’LVDS84A requires no external components and little or no control. The data bus appears the same at the input to the transmitter and output of the receiver with the data transmission transparent to the user(s). The only user intervention is the possible use of the shutdown/clear ($\overline{\text{SHTDN}}$) active-low input to inhibit the clock and shut off the LVDS output drivers for lower power consumption. A low-level on this signal clears all internal registers to a low level.

The SN75LVDS84A is characterized for operation over ambient free-air temperatures of 0°C to 70°C.

functional block diagram



schematics of input and output



absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage range, V_{CC} (see Note 1) . . . . . –0.5 V to 4 V
Input and output voltage ranges, V_I, V_O (all terminals) . . . . . –0.5 V to V_{CC} + 0.5 V
Continuous total power dissipation . . . . . See Dissipation Rating Table
Electrostatic discharge: ESD machine model . . . . . 200 V
ESD human-body model . . . . . 6000 V
ESD charged-device model . . . . . 1500 V
Storage temperature range, T_{stg} . . . . . –65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds . . . . . 260°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to the GND terminals.

DISSIPATION RATING TABLE

PACKAGE	$T_A \le 25°C$ POWER RATING	DERATING FACTOR‡ ABOVE $T_A = 25°C$	$T_A = 70°C$ POWER RATING
DGG	1316 mW	13.1 mW/°C	726 mW

‡ This is the inverse of the junction-to-ambient thermal resistance when board mounted and with no air flow.

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V_{CC}	3	3.3	3.6	V
High-level input voltage, V_{IH}	2			V
Low-level input voltage, V_{IL}			0.8	V
Differential load impedance, Z_L	90		132	Ω
Operating free-air temperature, T_A	0		70	°C

timing requirements

		MIN	NOM	MAX	UNIT
t_c	Input clock period	13.3	t_c	32.4	ns
t_w	Pulse duration, high-level input clock	$0.4t_c$		$0.6t_c$	ns
t_t	Transition time, input signal			5	ns
t_{su}	Setup time, data, D0 – D20 valid before CLKIN↓ (See Figure 2)	3			ns
t_h	Hold time, data, D0 – D20 valid after CLKIN↓ (See Figure 2)	1.5			ns

electrical characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{IT}	Input threshold voltage				1.4		V
$\|V_{OD}\|$	Differential steady-state output voltage magnitude	R_L = 100 Ω, See Figure 3		247		454	mV
$\Delta\|V_{OD}\|$	Change in the steady-state differential output voltage magnitude between opposite binary states					50	mV
$V_{OC(SS)}$	Steady-state common-mode output voltage	R_L = 100 Ω, See Figure 3		1.125		1.375	V
$V_{OC(PP)}$	Peak-to-peak common-mode output voltage				80	150	mV
I_{IH}	High-level input current	$V_{IH} = V_{CC}$				20	µA
I_{IL}	Low-level input current	V_{IL} = 0				±10	µA
I_{OS}	Short-circuit output current	$V_{O(Yn)}$ = 0			–6	±24	mA
		V_{OD} = 0			–6	±12	mA
I_{OZ}	High-impedance output current	V_O = 0 to V_{CC}				±10	µA
$I_{CC(AVG)}$	Quiescent supply current (average)	Disabled, All inputs at GND			15	150	µA
		Enabled, R_L = 100 Ω (4 places) Gray-scale pattern (see Figure 4)	f = 65 MHz		27	35	mA
			f = 75 MHz		30	38	
		Enabled, R_L = 100 Ω, (4 places) Worst-case pattern (see Figure 5)	f = 65 MHz		28	36	
			f = 75 MHz		31	39	
C_I	Input capacitance				2		pF

† All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

switching characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP†	MAX	UNIT
t_{d0}	Delay time, CLKOUT↑ to serial bit position 0	t_c = 15.38 ns (± 0.2%), |Input clock jitter| < 50 ps‡, See Figure 6	−0.2		0.2	ns
t_{d1}	Delay time, CLKOUT↑ to serial bit position 1		$\frac{1}{7}t_c$ − 0.2		$\frac{1}{7}t_c$ + 0.2	
t_{d2}	Delay time, CLKOUT↑ to serial bit position 2		$\frac{2}{7}t_c$ − 0.2		$\frac{2}{7}t_c$ + 0.2	
t_{d3}	Delay time, CLKOUT↑ to serial bit position 3		$\frac{3}{7}t_c$ − 0.2		$\frac{3}{7}t_c$ + 0.2	
t_{d4}	Delay time, CLKOUT↑ to serial bit position 4		$\frac{4}{7}t_c$ − 0.2		$\frac{4}{7}t_c$ + 0.2	
t_{d5}	Delay time, CLKOUT↑ to serial bit position 5		$\frac{5}{7}t_c$ − 0.2		$\frac{5}{7}t_c$ + 0.2	
t_{d6}	Delay time, CLKOUT↑ to serial bit position 6		$\frac{6}{7}t_c$ − 0.2		$\frac{6}{7}t_c$ + 0.2	
$t_{sk(o)}$	Output skew, $t_n - \frac{n}{7}t_c$		−0.2		0.2	ns
t_{d7}	Delay time, CLKIN↓ to CLKOUT↑	t_c = 15.38 ns (± 0.2%), |Input clock jitter| < 50 ps‡, See Figure 6		2.7		ns
		t_c = 13.33 ns ~ 32.25 ns (± 0.2%), |Input clock jitter| < 50 ps‡, See Figure 6	1		4.5	
$\Delta t_{c(o)}$	Cycle time, output clock jitter§	t_c = 15.38 + 0.308 sin (2π500E3t) ± 0.05 ns, See Figure 7		±62		ps
		t_c = 15.38 + 0.308 sin (2π3E6t) ± 0.05 ns, See Figure 7		±121		
t_w	Pulse duration, high-level output clock			$\frac{4}{7}t_c$		ns
t_t	Transition time, differential output voltage (t_r or t_f)	See Figure 3		700	1500	ps
t_{en}	Enable time, $\overline{SHTDN}$↑ to phase lock (Yn valid)	See Figure 8		1		ms
t_{dis}	Disable time, $\overline{SHTDN}$↓ to off state (CLKOUT low)	See Figure 9		6.5		ns

† All typical values are at V_{CC} = 3.3 V, T_A = 25°C.
‡ |Input clock jitter| is the magnitude of the change in the input clock period.
§ Output clock jitter is the change in the output clock period from one cycle to the next cycle observed over 15000 cycles.

PARAMETER MEASUREMENT INFORMATION

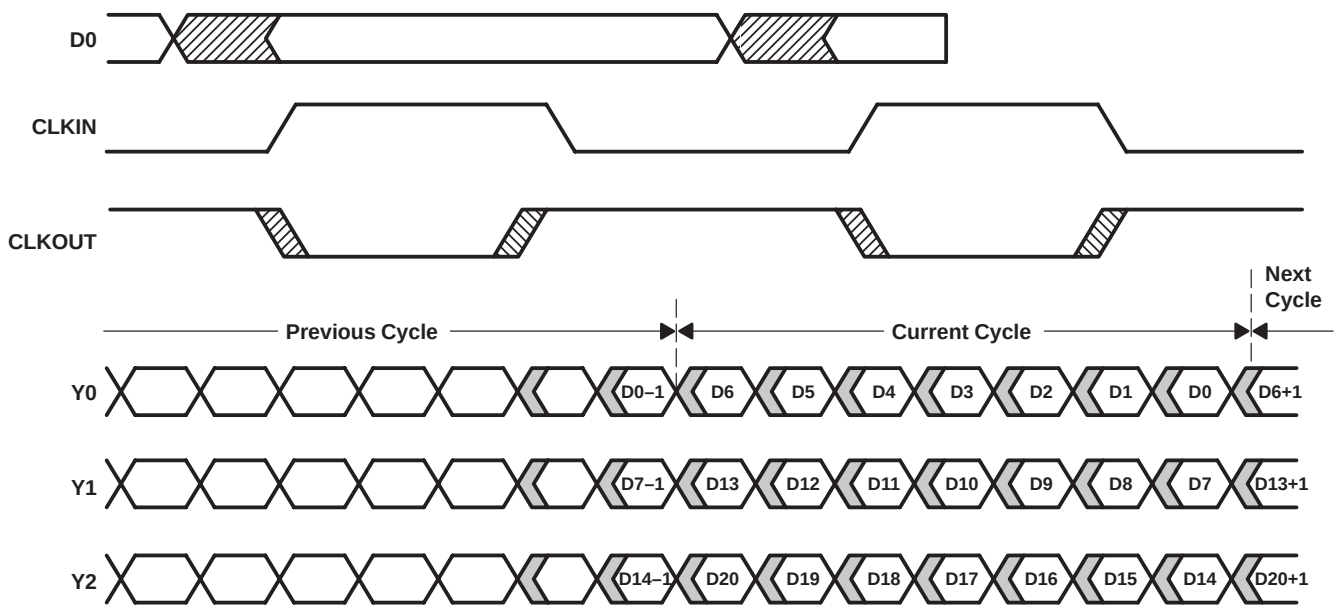
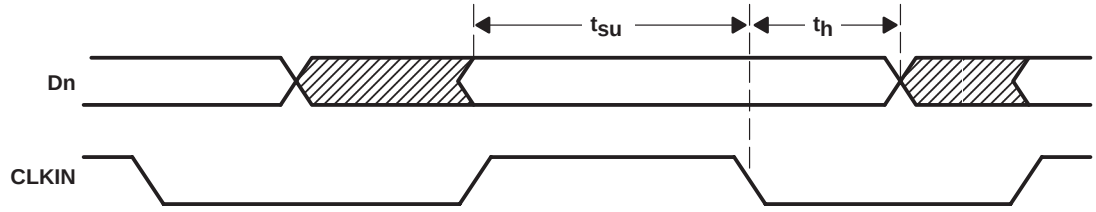
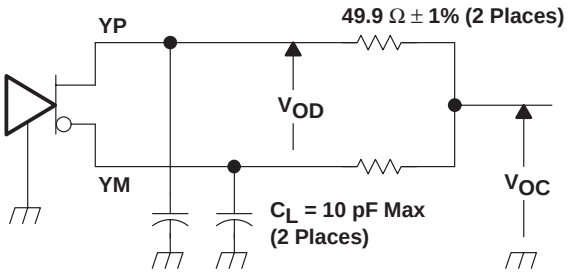


Figure 1. Typical Load and Shift Sequences



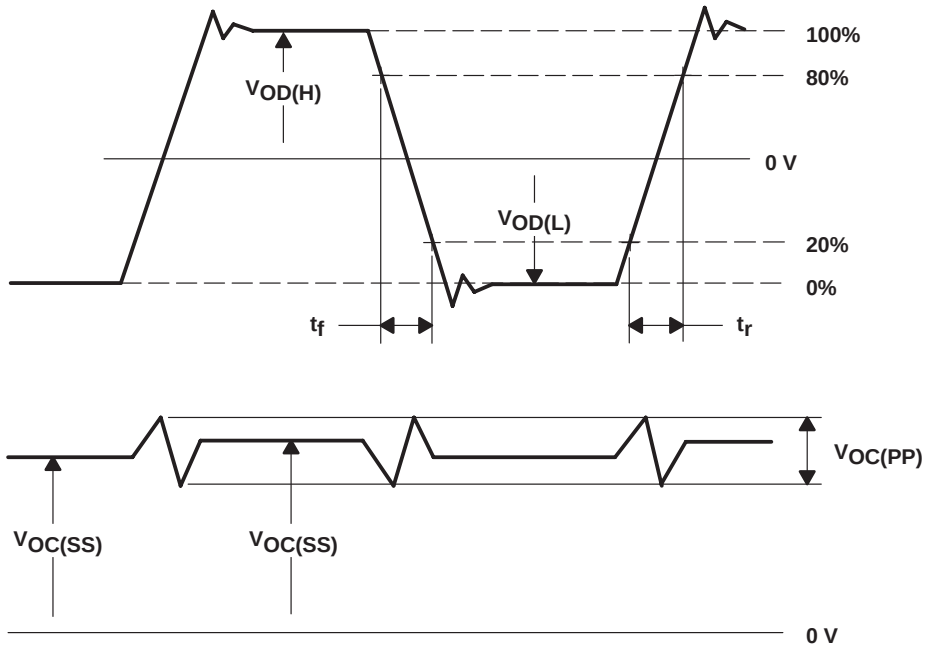
NOTE A: All input timing is defined at 1.4 V on an input signal with a 10%-to-90% rise or fall time of less than 5 ns.

Figure 2. Setup and Hold Time Definition



NOTE A: The lumped instrumentation capacitance for any single-ended voltage measurement is less than or equal to 10 pF. When making measurements at YP or YM, the complementary output is similarly loaded.

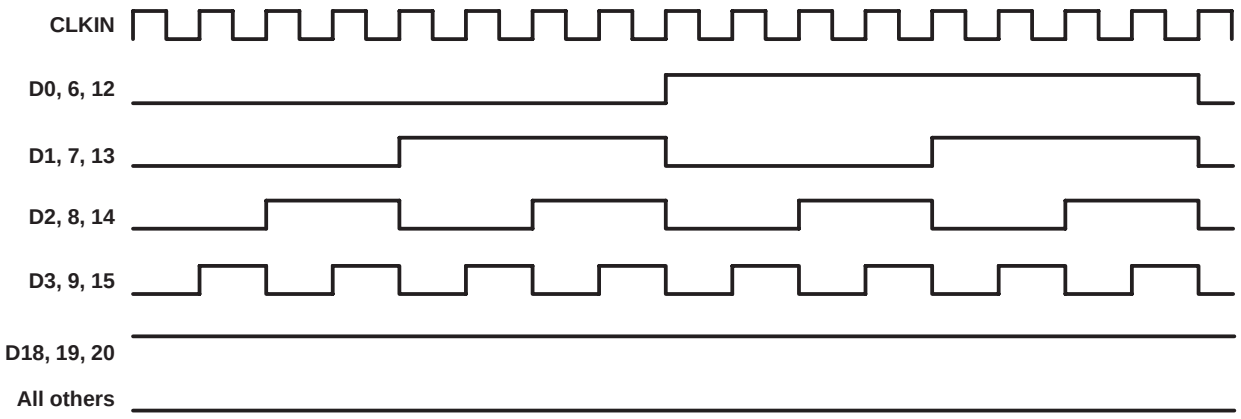
(a) SCHEMATIC



(b) WAVEFORMS

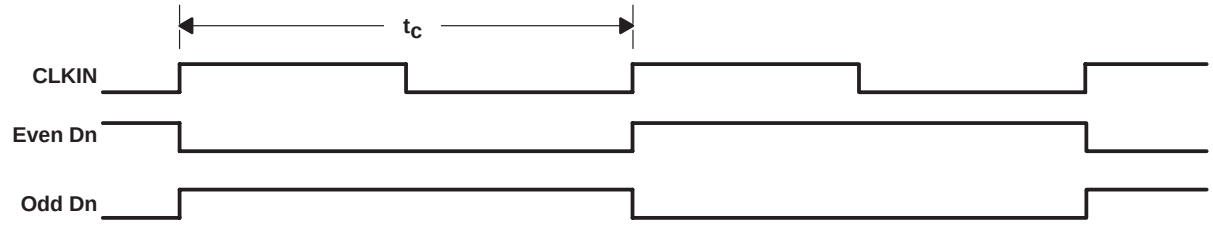
Figure 3. Test Load and Voltage Definitions for LVDS Outputs

PARAMETER MEASUREMENT INFORMATION



NOTES: A. The 16-grayscale test-pattern test device power consumption for a typical display pattern.
B. V_{IH} = 2 V and V_{IL} = 0.8 V

Figure 4. 16-Grayscale Test-Pattern Waveforms



NOTES: A. The worst-case test pattern produces nearly the maximum switching frequency for all of the LVDS outputs.
B. V_{IH} = 2 V and V_{IL} = 0.8 V

Figure 5. Worst-Case Test-Pattern Waveforms

PARAMETER MEASUREMENT INFORMATION

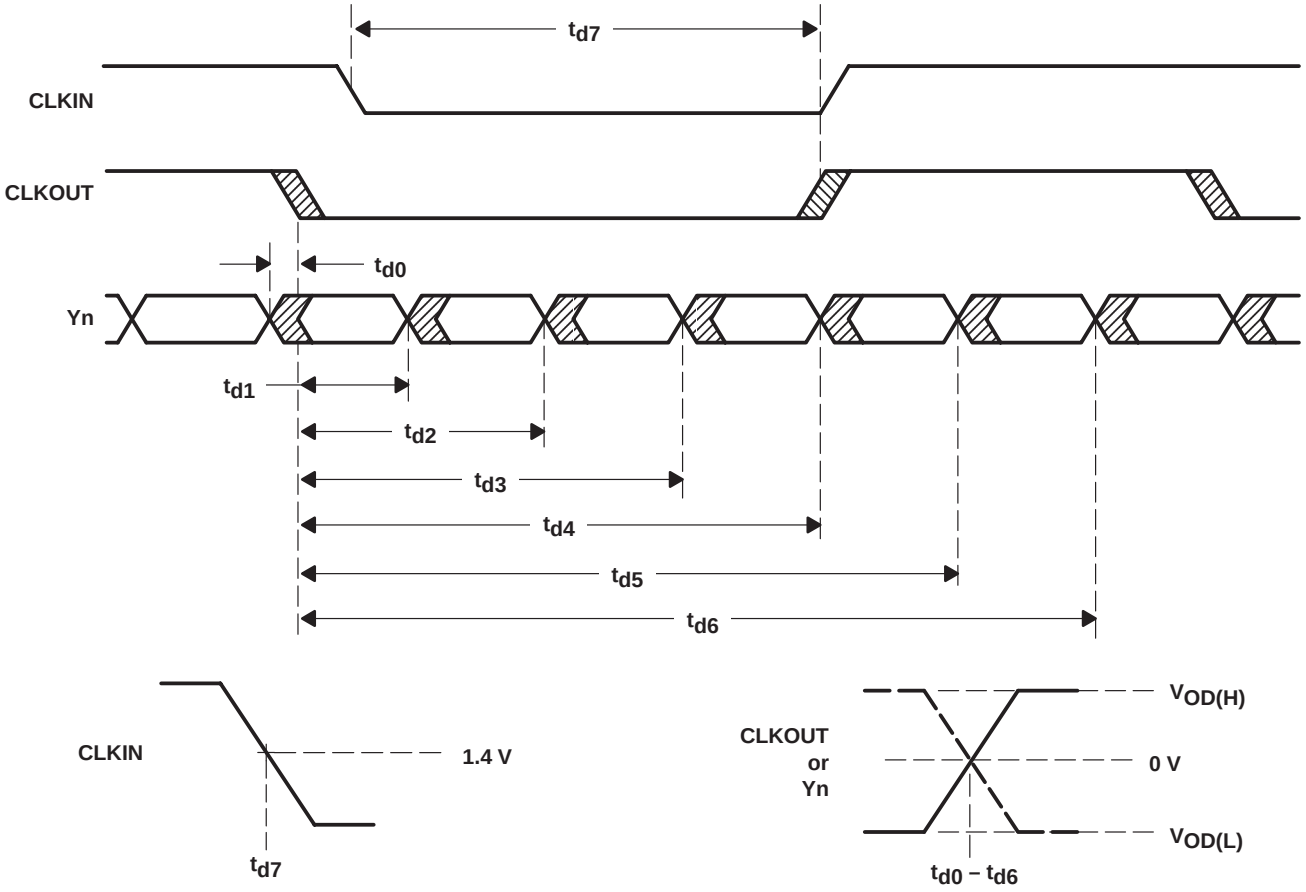


Figure 6. Timing Definitions

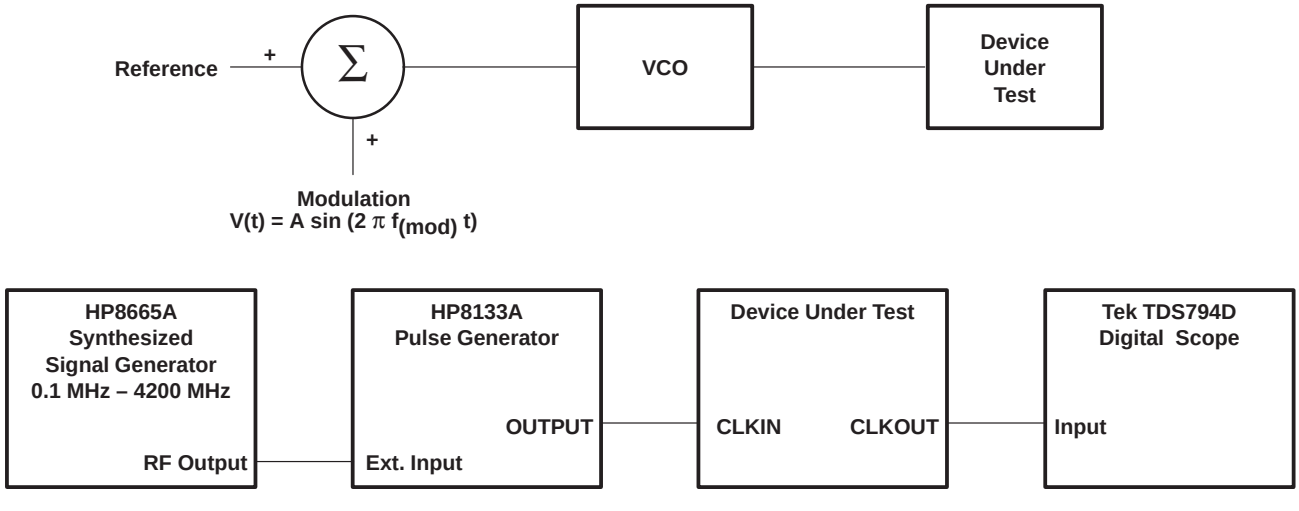


Figure 7. Clock Jitter Test Setup

TYPICAL CHARACTERISTICS

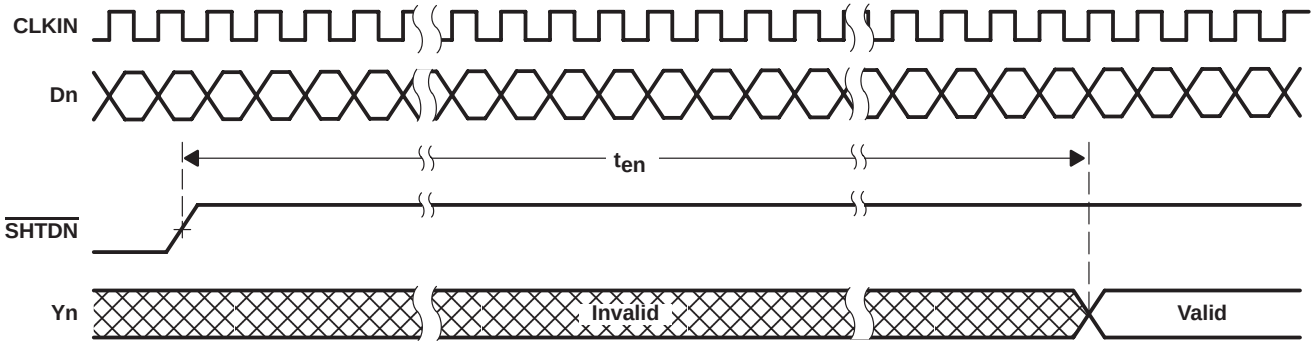


Figure 8. Enable Time Waveforms

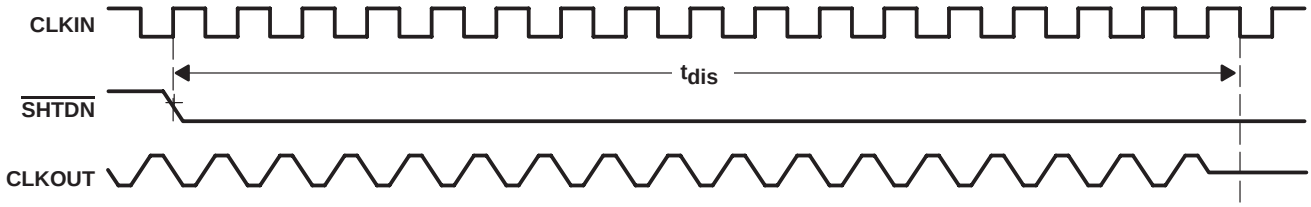


Figure 9. Disable Time Waveforms

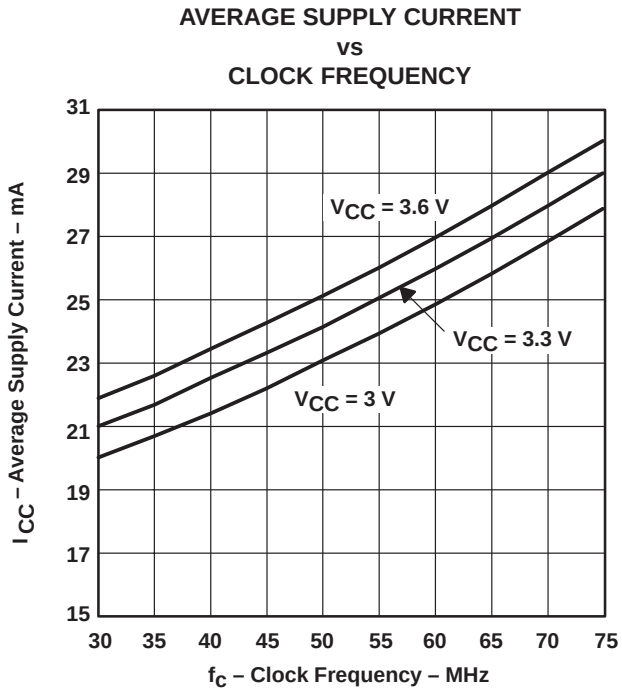


Figure 10. Grayscale Input Pattern

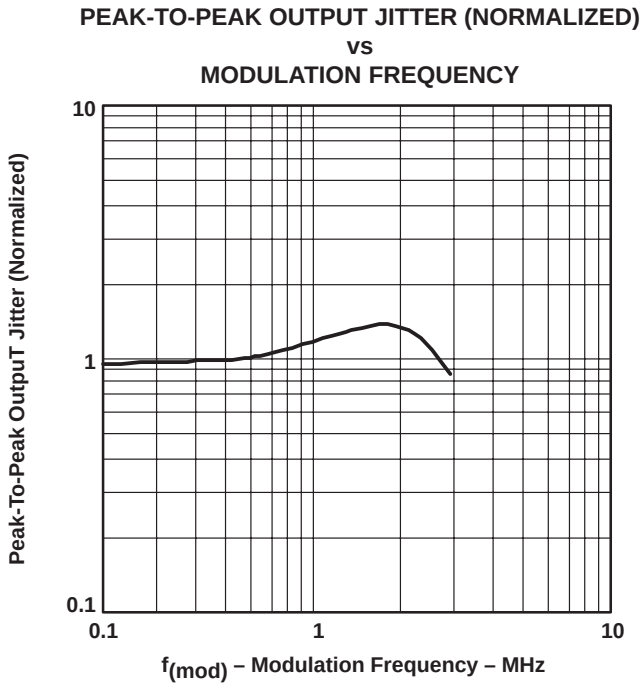
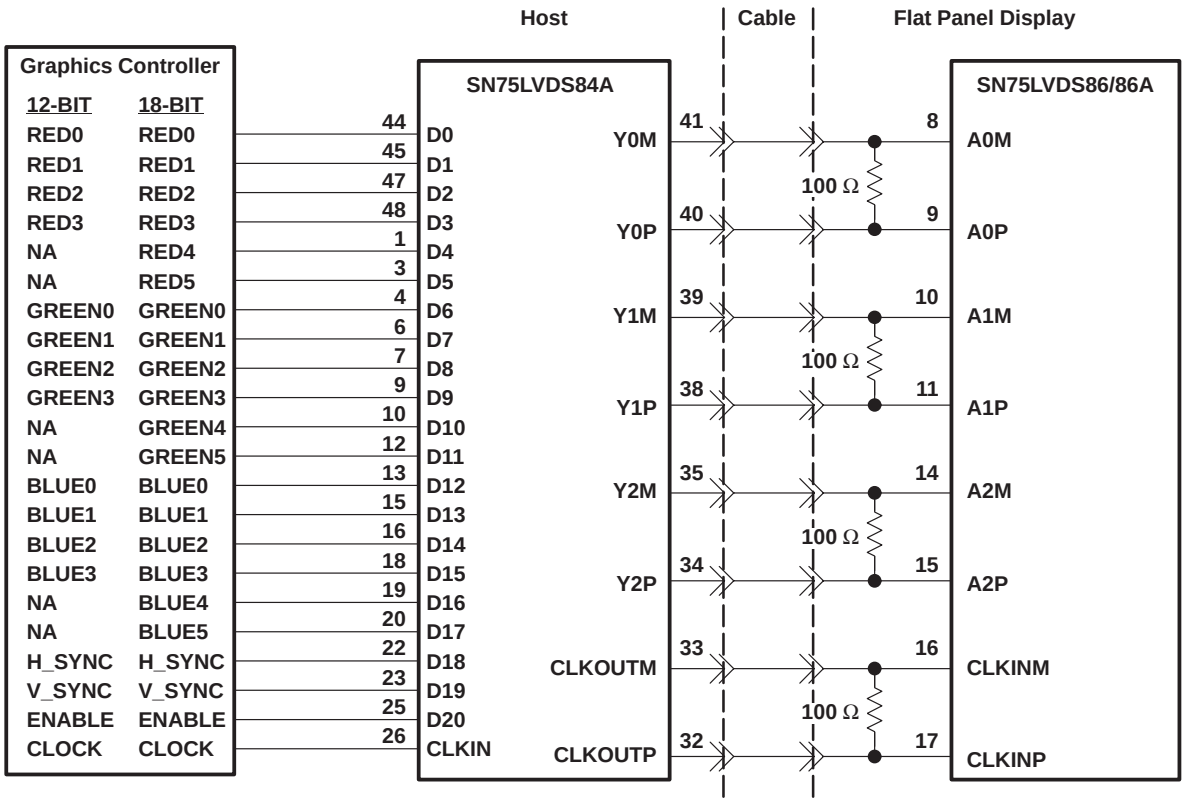


Figure 11. Output Period Jitter vs Modulation Frequency

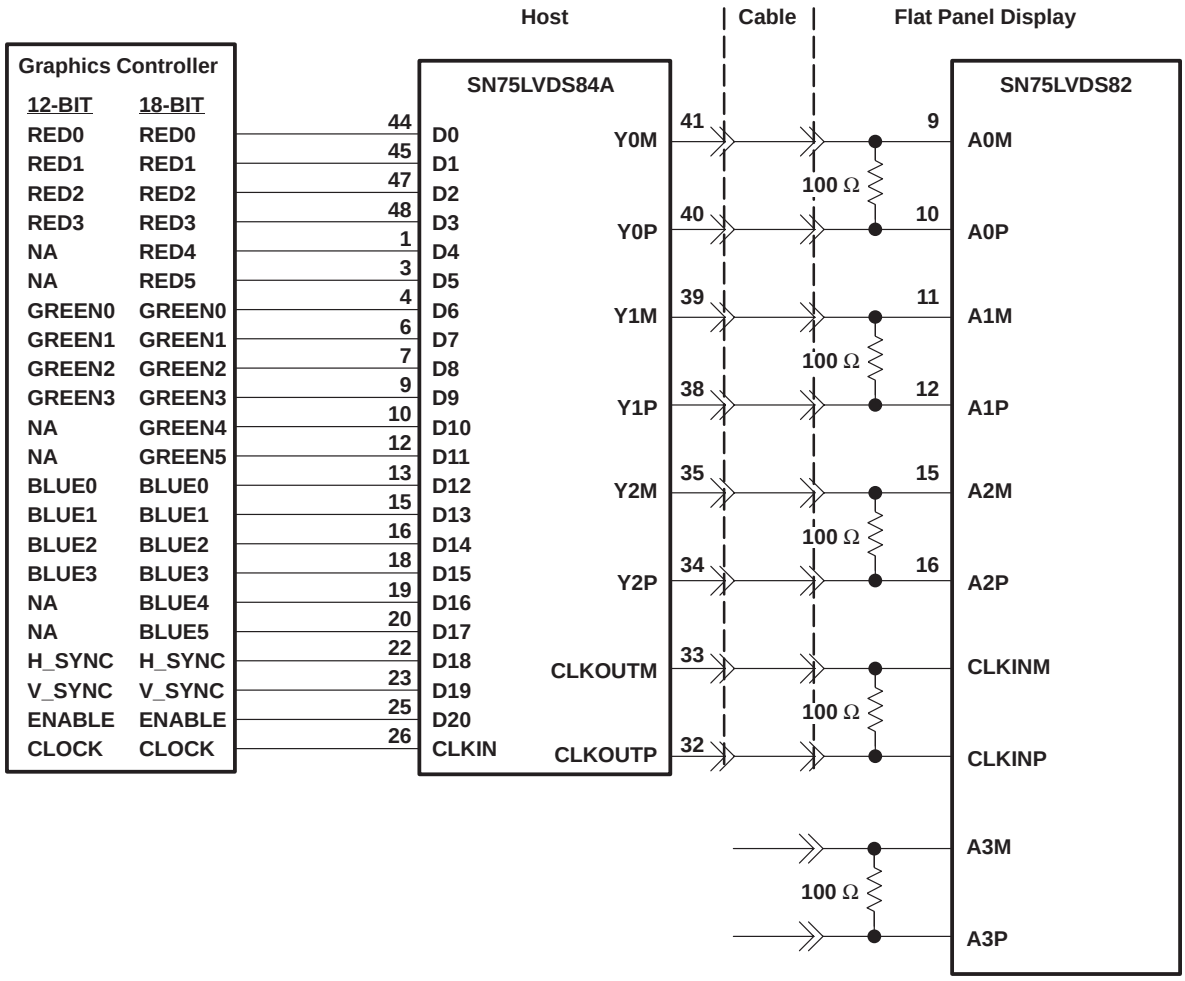
APPLICATION INFORMATION



NOTES: A. The five 100-Ω terminating resistors are recommended to be 0603 types.
B. NA – not applicable, these unused inputs should be left open.

Figure 12. Color Host to LCD Panel Application

APPLICATION INFORMATION



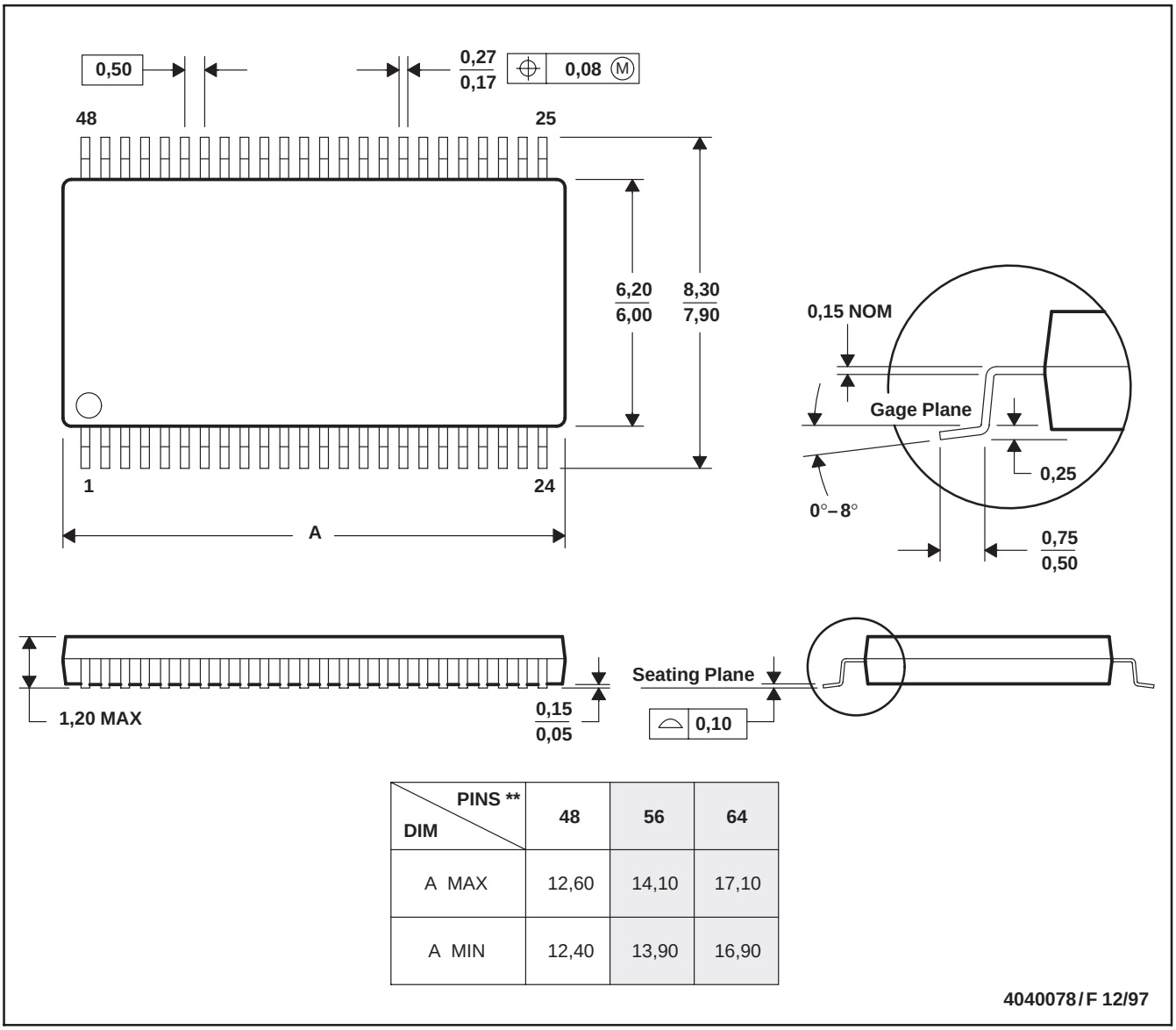
NOTES: A. The four 100-Ω terminating resistors are recommended to be 0603 types.
B. NA – not applicable, these unused inputs should be left open.

Figure 13. 18-Bit Color Host to 24-Bit LCD Display Panel Application

MECHANICAL INFORMATION

DGG (R-PDSO-G)** **PLASTIC SMALL-OUTLINE PACKAGE**

48 PIN SHOWN



DIM \ PINS **	48	56	64
A MAX	12,60	14,10	17,10
A MIN	12,40	13,90	16,90

4040078/F 12/97

NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold protrusion not to exceed 0,15.
D. Falls within JEDEC MO-153

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